L Number	Hits	Search Text	DB	Time stamp
1	1214	("fanout") and (test$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:06
2	2160	("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:29
4	37	(("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).clm.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:12
5	0	(("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:29
3	14	(("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:08
6	36	((("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).clm.) not ((("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).ab.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:12
7	52	(("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")) and 714/724.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:29
8	7	((("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).ab. (("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).ti. (("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).clm.) and 714/724.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:30
9	9	((("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).ab. (("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).ti. (("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).clm.) and 714/726.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:30
10	0	((("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).ab. (("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).ti. (("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).clm.) and 714/742.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:30
11	5	((("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).ab. (("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).ti. (("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).clm.) and 714/738.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:30
12	0	((("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).ab. (("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).ti. (("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).clm.) and 714/739.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:31

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13	0	((("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).ab. (("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).ti. (("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).clm.) and 714/733.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:31
14	0	((("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).ab. (("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).ti. (("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).clm.) and 714/728.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:31
15	1	((("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).ab. (("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).ti. (("fanout" "fan out") and (test$3) and (latch$3 register$2 flipflop "flip-flop" "flip flop")).clm.) and 714/727.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/18 15:31
-	1403	((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ti. ((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 12:59
-	68	(((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ti. ((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ab.) and (relay relays)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 12:59
-	310	(((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ti. ((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ab.) and (relay relays switch switches)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/09 11:56
-	60	((((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ti. ((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ab.) and (relay relays switch switches)) and ((clock clocks) with (latch "shift register" flip-flop flipflop register))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/09 16:21
-	885	714/704.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/09 12:00
-	0	(((((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ti. ((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ab.) and (relay relays switch switches)) and ((clock clocks) with (latch "shift register" flip-flop flipflop register))) and (fan-out "fan out" fanout)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/09 12:06
-	1408020	DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/09 16:26

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-	311	(((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ti. ((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ab.) and (relay relays switch switches)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 13:07
-	16361	(DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 13:13
-	25770	(DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test (circuit near test$3)) and (test near (data signal input pattern source information))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 13:54
-	4957	"5" and (((relay relays relayed relaying switch switching switched switches) with circuit) and ((fanout "fan out" serial-to-parallel multiplex$3) near (relay relays relayed relaying switch switching switched switches)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 14:45
-	1284	("5" and (((relay relays relayed relaying switch switching switched switches) with circuit) and ((fanout "fan out" serial-to-parallel multiplex$3) near (relay relays relayed relaying switch switching switched switches)))) and (latch and clock)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 14:47

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